

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/580,822	BIGARRE ET AL.	
	Examiner	Art Unit	Page 1 of 1
Manuel L. Barbee	2857		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,395,242 A	07-1983	Liller et al.	445/5
*	B	US-6,338,790 B1	01-2002	Feldman et al.	205/777.5
C	US-				
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J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Bigarre, J. et al.: "Trapping of Electrical Charges and Laser Damage", May 2003, Proceedings of the International Society for Optical Engineering, Volume 4932, pages 258-267.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.